~~Claims~~

> IN THE CLAIMS

1. An x-ray examination apparatus comprising

- an x-ray image sensor matrix (1) for deriving an initial image signal from an x-ray image,

- a correction unit (2) for deriving a corrected image signal from the initial image signal

characterised in that

- the correction unit (2) includes a
- memory (3) for storing correction values and
- an arithmetic unit (4) for computing signal levels of the corrected image signal from signal levels of the initial image signal and at least some of said correction values.

2. An x-ray examination apparatus as claimed in Claim 1, characterised in that

- the correction unit (2) includes a selection unit (5) for selecting correction values from the memory (3) on the basis of exposure parameters.

3. An x-ray examination apparatus as claimed in Claim 2, characterised in that

- the correction unit (2) is arranged to generate a

reference image signal from the x-ray sensor matrix (1),

- the selection unit (5) is arranged to select the correction values on the basis of the reference image signal.

4. An x-ray examination apparatus as claimed in any one of the preceding Claims, characterised in that

- the arithmetic unit (4) is arranged to compute correction values from stored correction values.

5. An x-ray examination apparatus as claimed in Claim 4, characterised in that

- the arithmetic unit (4) is arranged to interpolate said computed correction values between stored correction values.